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"Multiscale structure properties in electrospun nanofiber scaffolds: process understanding to steer mechanical behaviors" A. K. Maurya, E. Mias, J. Schoeller, I. Collings, R. M. Rossi, A. Dommann, A. Neels; *Nanoscale Advances*

"Lattice strain and defects analysis in nanostructured semiconductor materials and devices by high-resolution X-ray diffraction: theoretical and practical aspects" S. Dolabella, A. Borzi, A. Dommann, A. Neels; *Small Methods*

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